



Contribution ID: 1458

Type: **Invited Speaker / Conférencier invité**

Integrated Testlets: Multiple-Choice Testing 2.0

Thursday 16 June 2016 09:00 (30 minutes)

Multiple-choice (MC) exams are becoming more prevalent in physics courses as student populations rise and instructional resources dwindle. Particularly in STEM disciplines we would like to find ways to test deeper levels of understanding or knowledge integrations than are typically afforded by multiple-choice tests. With simple immediate-feedback tools we can construct new types of multiple-choice assessment structures that test both higher-level thinking, and knowledge integration. Such “Integrated Testlets”(ITs) also add the benefits of simple and valid granting of partial credit, as well as turning a final exam into a formative assessment opportunity. In this talk, I will touch on the antagonism between constructed-response and multiple-choice testing in physics, I will outline how ITs resolve some of this antagonism, I will summarize recent data on the validity of partial credit in MC testing, and I will briefly review the development and current usage of ITs.

Author: SLEPKOV, Aaron (Trent University)

Co-author: Dr SHIELL, Ralph (Trent University)

Presenter: SLEPKOV, Aaron (Trent University)

Session Classification: R1-1 Interactive Teaching: Teaching with Technology (DPE) / Enseignement interactif et à l'aide de la technologie (DEP)

Track Classification: Physics Education / Enseignement de la physique (DPE-DEP)